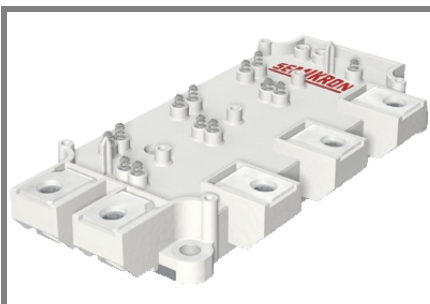


SEMiX 151GD066HDs



SEMiX® 13s

Trench IGBT Modules

SEMiX 151GD066HDs

Preliminary Data

Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient

Typical Applications

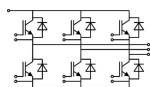
- Matrix Converter
- Resonant Inverter
- Current Source Inverter

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_j=150^\circ\text{C}$
- use of soft RG necessary
- take care of over-voltage caused by stray inductance

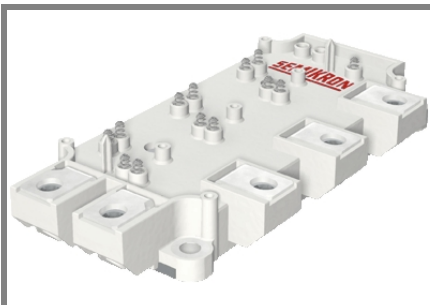
Absolute Maximum Ratings		$T_{case} = 25^\circ\text{C}$, unless otherwise specified		
Symbol	Conditions	Values	Units	
IGBT				
V_{CES}	$T_j = 25^\circ\text{C}$	600	V	
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	200	A
		$T_c = 80^\circ\text{C}$	150	A
I_{CRM}	$I_{CRM} = 2 \times I_{Cnom}$	300	A	
V_{GES}		± 20	V	
t_{psc}	$V_{CC} = 360\text{ V}; V_{GE} \leq 15\text{ V}; T_j = 150^\circ\text{C}$ $V_{CES} < 600\text{ V}$	6	μs	
Inverse Diode				
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	220	A
		$T_c = 80^\circ\text{C}$	160	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	300	A	
I_{FSM}	$t_p = 10\text{ ms}; \sin.$	$T_j = 25^\circ\text{C}$	980	A
Module				
$I_{t(RMS)}$		600	A	
T_{vj}		- 40 ... + 175 (125)	$^\circ\text{C}$	
T_{stg}		- 40 ... + 125	$^\circ\text{C}$	
V_{isol}	AC, 1 min.	4000	V	

Characteristics		$T_{case} = 25^\circ\text{C}$, unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
IGBT					
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 2,4\text{ mA}$		5,8		V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}$			0,45	mA
V_{CE0}		$T_j = 25^\circ\text{C}$	0,9	1	V
		$T_j = 150^\circ\text{C}$	0,85	0,9	V
r_{CE}	$V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}$	3,7	6	m Ω
		$T_j = 150^\circ\text{C}$	5,7	8	m Ω
$V_{CE(sat)}$	$I_{Cnom} = 150\text{ A}, V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}_{chiplev.}$	1,45	1,9	V
		$T_j = 150^\circ\text{C}_{chiplev.}$	1,7	2,1	V
C_{ies}	$V_{CE} = 25, V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	9,2		nF
C_{oes}			0,6		nF
C_{res}			0,28		nF
Q_G	$V_{GE} = -8 \dots +15\text{ V}$		1200		nC
$t_{d(on)}$	$R_{Gon} = 4,5\ \Omega$	$V_{CC} = 300\text{ V}$ $I_{Cnom} = 150\text{ A}$	140		ns
t_r			40		ns
E_{on}	$R_{Goff} = 4,5\ \Omega$	$T_j = 150^\circ\text{C}$	3,8		mJ
$t_{d(off)}$			385		ns
t_f			40		ns
E_{off}			6,1		mJ
$R_{th(j-c)}$	per IGBT			0,29	K/W



GD

SEMiX 151GD066HDs



SEMiX® 13s

Trench IGBT Modules

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Preliminary Data

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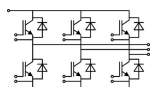
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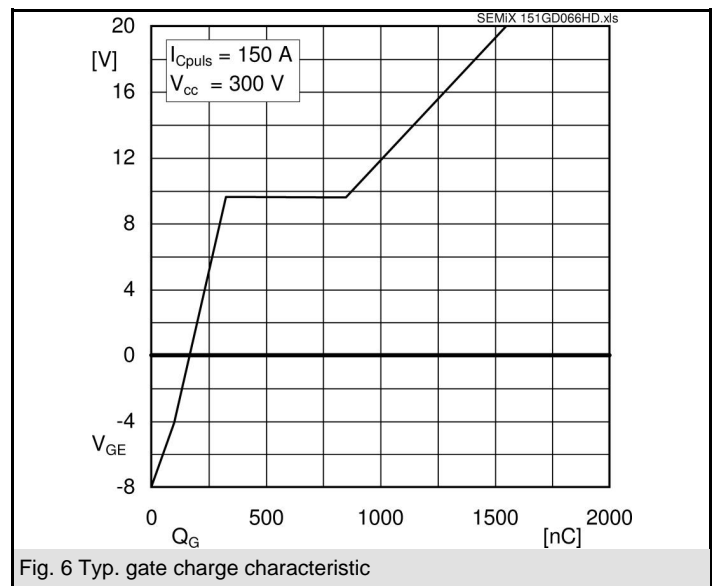
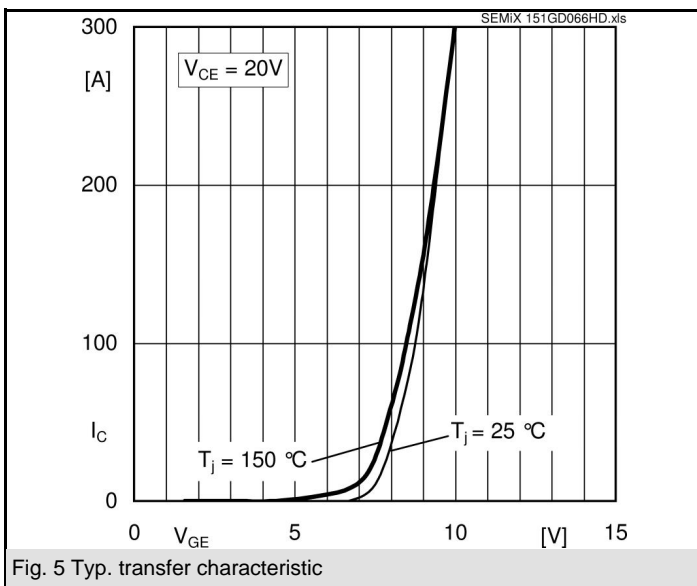
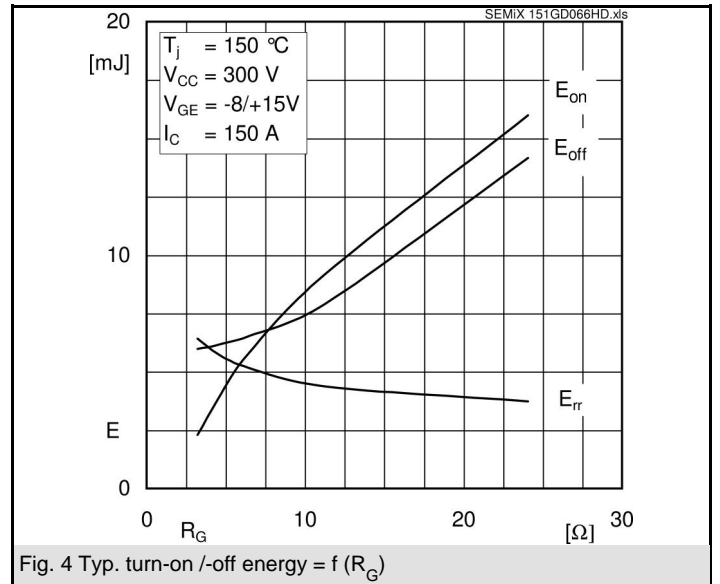
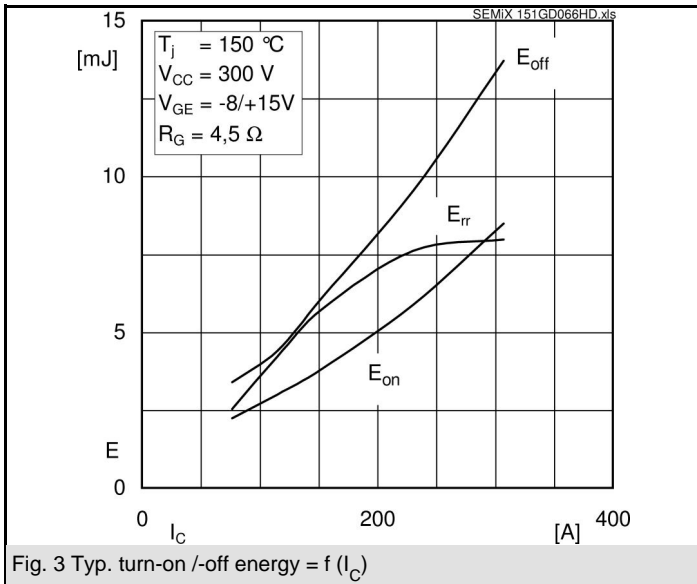
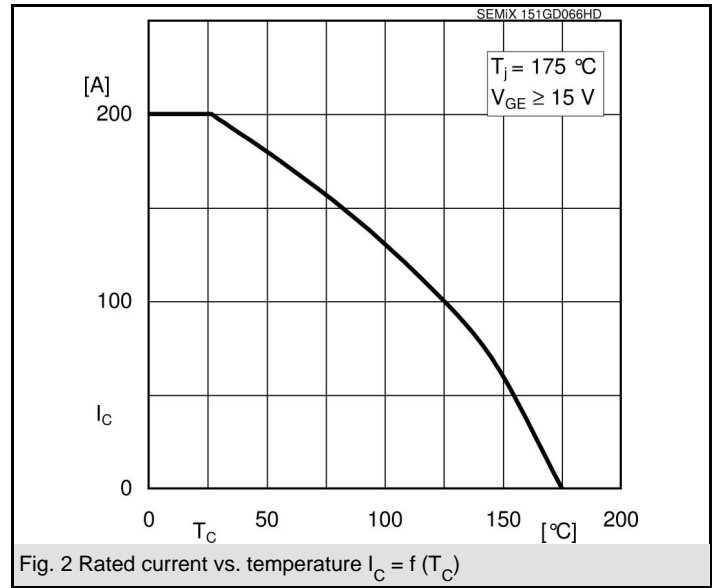
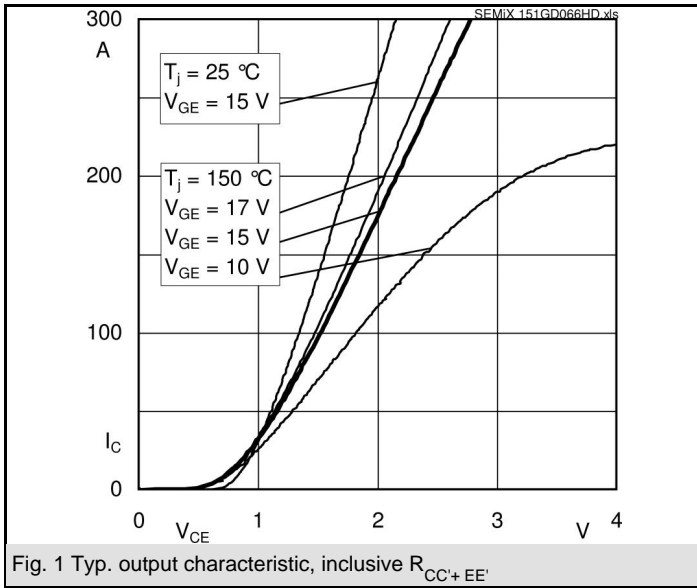


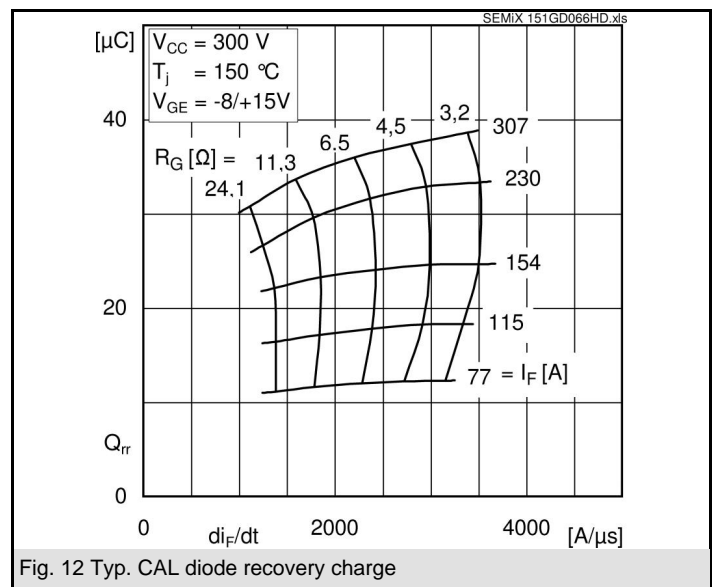
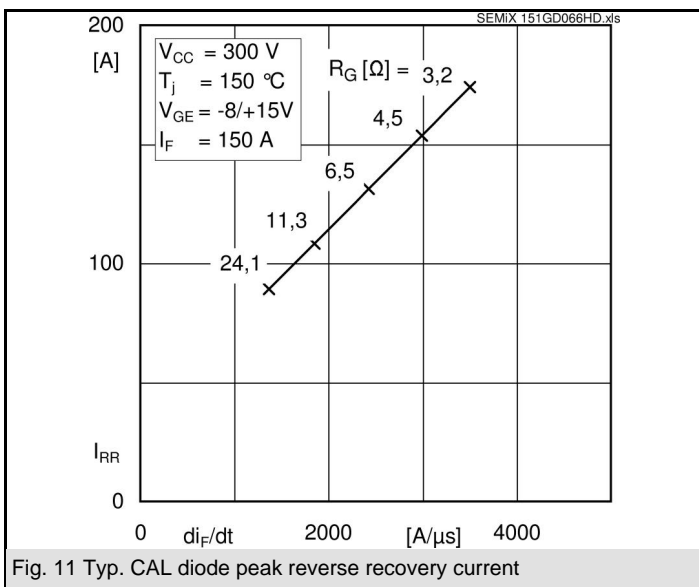
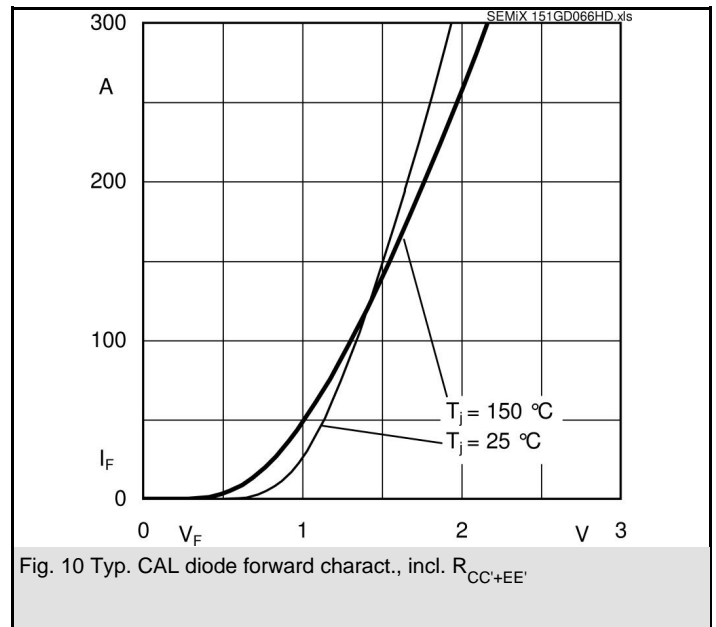
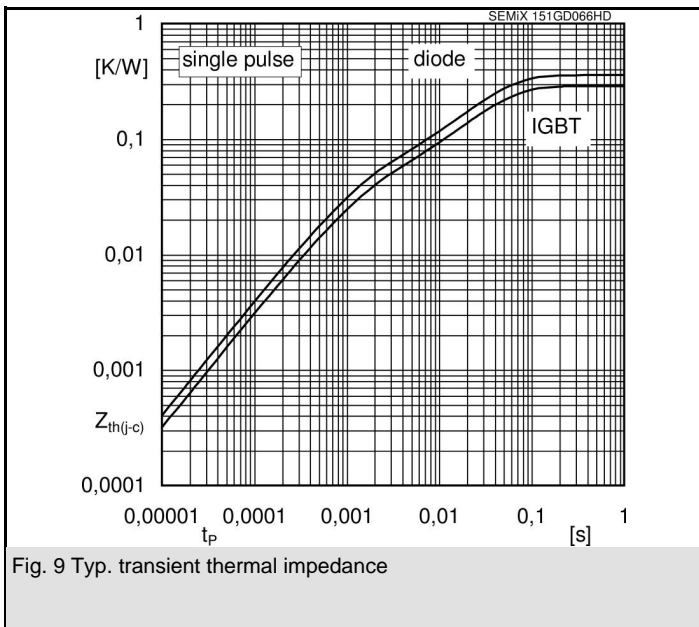
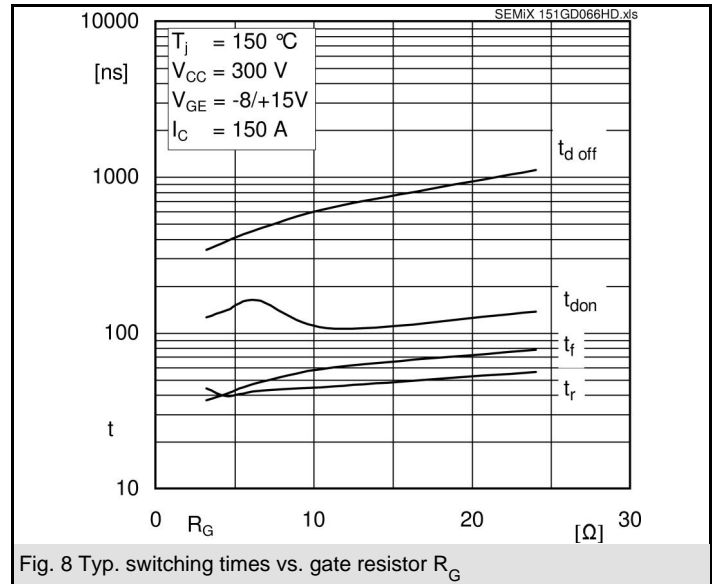
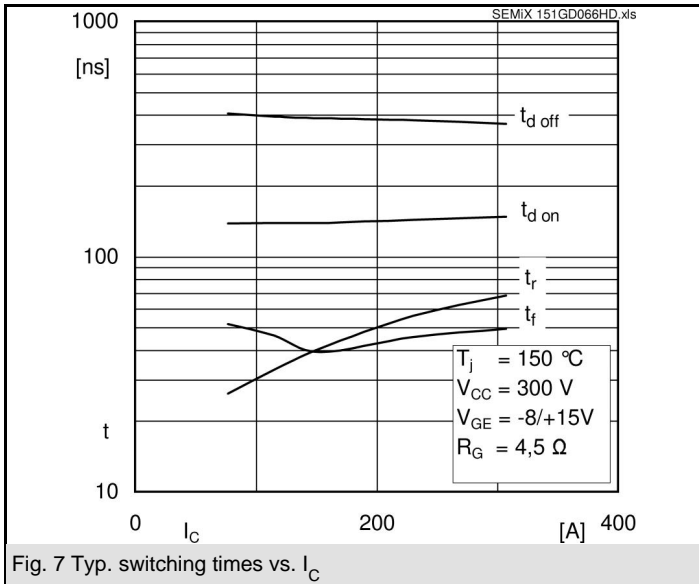
GD

Characteristics		min.	typ.	max.	Units
Inverse Diode					
$V_F = V_{EC}$	$I_{Fnom} = 150\text{ A}; V_{GE} = 0\text{ V}$		1,4	1,6	V
	$T_j = 25^\circ\text{C}_{chiplev.}$				
	$T_j = 150^\circ\text{C}_{chiplev.}$		1,4	1,6	V
V_{F0}			1	1,1	V
	$T_j = 25^\circ\text{C}$				
	$T_j = 150^\circ\text{C}$		0,85	0,95	V
r_F			2,7	3,5	mΩ
	$T_j = 25^\circ\text{C}$				
	$T_j = 150^\circ\text{C}$		3,7	4,5	mΩ
I_{RRM}	$I_{Fnom} = 150\text{ A}$		155		A
Q_{rr}	$di/dt = 3000\text{ A}/\mu\text{s}$		24		μC
E_{rr}	$V_{GE} = -8\text{ V}; V_{CC} = 300\text{ V}$		5,8		mJ
$R_{th(j-c)D}$	per diode			0,36	K/W
Module					
L_{CE}			20		nH
$R_{CC'+EE'}$	res., terminal-chip	$T_{case} = 25^\circ\text{C}$	0,7		mΩ
		$T_{case} = 125^\circ\text{C}$	1		mΩ
$R_{th(c-s)}$	per module		0,04		K/W
M_s	to heat sink (M5)		3	5	Nm
M_t	to terminals (M6)		2,5	5	Nm
w				350	g
Temperature sensor					
R_{100}	$T_c = 100^\circ\text{C}$ ($R_{25} = 5\text{ k}\Omega$)		0,493±5%		kΩ
$B_{100/125}$	$R(T) = R_{100} \exp[B_{100/125} (1/T - 1/T_{100})]$ $T[\text{K}]; B$		3550±2%		K

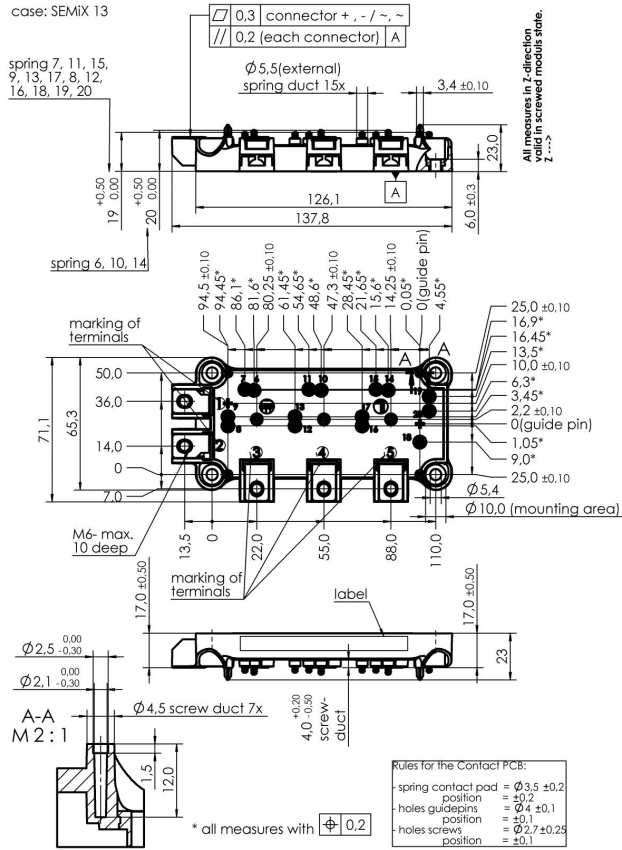
This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.





SEMiX 151GD066HDs



Case SEMiX 13s

